

Application/Control No.	Applicant(s)/Patent under Reexamination
09/892,010	CHEN, XUEMIN
Examiner	Art Unit
Nhon T. Dien	2613

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
Interfer	sence:	Scarch 1	43topy	
Print-	out	1/9/06	V.D.	
	(Inclue	ded)		
		9		

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
Inventor Search	1/9/05	N.D.			
updated Scarch (Included)	1/9/05	N.D.			
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